	L #	Hits	Search Text
1	L1	2	(scan adj circuit) and clock and enable and test and (self adj timed)
2	L2	5	(scan adj circuit) and (self adj timed)
3	L3	462	(scan adj circuit) and clock and enable
4	L4	190	3 and multiplexer
5	L5	0	asychronous and (scan adj circuit)
6	L6	0	asychronous and 326/121.ccls.
7	L7	38	asynchronous and 326/121.ccls.
8	L8	110	asynchronous and (scan adj circuit)
9	L9	67	8 and multiplexer
10	L10	1851287	9a dn mode
11	L11	59	9 and mode

	L #	Hits	Search Text	DBs	Time Stamp
1	L1	22	multiplexer and test and latch and timing and enable and (scan adj circuit)	US-PGPUB	2005/07/27 16:01

INTERFERENCE SEARCH